

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Application Serial No. .... 10/803,264  
Filing Date ..... March 17, 2004  
Inventor ..... Warren M. Farnworth et al.  
Assignee ..... Micron Technology, Inc.  
Group Art Unit ..... 2829  
Examiner ..... R. Kobert  
Attorney's Docket No. .... MI22-2524  
Title: Method and Apparatus for Testing Semiconductor Circuitry for Operability and  
Method of Forming Apparatus for Testing Semiconductor Circuitry for Operability

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

Reference - - See attached Form PTO-1449

The attached Form PTO-1449 is submitted in compliance with 37 C.F.R. §§ 1.56.  
Pursuant to Federal Register Vol. 69, No. 182, pg. 56542 (September 21, 2004), no copies  
of any cited U.S. patents or U.S. published applications are included herewith. No  
admission is made regarding whether the submitted reference is prior art.

Citation of this reference is respectfully requested.

Respectfully submitted,

Date: 2-28-05



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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MJ22-2524		SERIAL NO. 10/803,264	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Warren M. Farworth et al.			
				FILING DATE March 17, 2004		GROUP 2829	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	4,700,132	10/87	Yarbrough et al.			
	AB						
	AC						
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	AG						
	AH						
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FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
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